

RSK 175 – Low Level

It is often stipulated that a particular method be used to measure dissolved methane, ethane and ethene (MEE). The technical reason for that measurement is straightforward: the methane is a byproduct of the reactions that facilitate reductive dechlorination, and the ethane and ethene are the end-products of dechlorination. The choice of method is considerably less straightforward.

RSK 175 describes a procedure particular to the R.S. Kerr USEPA Laboratory in Ada, OK. It is not a promulgated method. The work-group that develops methods for the EPA is tasked with developing methods to measure hazardous contaminants, and MEE is not hazardous. However, the scientists at Ada developed RSK 175 as a high quality, defensible and documented way to measure MEE and have been gracious enough to share it with many laboratories.

PAES scientists realized that it was important to look at concentrations below those measurable with RSK 175. AM20Gax was developed to measure very low MEE concentrations, but because it was not strictly an RSK 175 method, many practitioners could not use it.

RSK 175 – Low Level Reporting Limits	
Methane	0.5 ug/L
Ethane	0.2 ug/L
Ethene	0.2 ug/L

Pace Energy's RSK 175 is a combination of the technology behind the high sensitivity of AM20Gax and the quality control program of RSK 175.

Our RSK 175 technique gives the superior sensitivity and the more widely recognized quality assurance of RSK 175.

The reporting limits of AM20Gax are still lower than the RSK 175 Low Level. For that reason, PAES routinely recommends AM20Gax for MEE. However, if RSK 175 is required, we can supply it whenever requested with superior detection limits.

